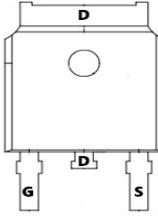
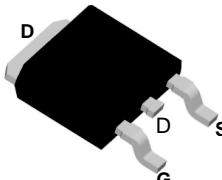
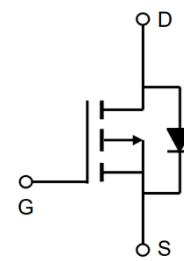


**TM100P06D**
**P -Channel Enhancement Mosfet**

<p><b>General Description</b></p> <ul style="list-style-type: none"> <li>• Low <math>R_{DS(ON)}</math></li> <li>• RoHS and Halogen-Free Compliant</li> </ul> <p><b>Applications</b></p> <ul style="list-style-type: none"> <li>• Load switch</li> <li>• PWM</li> </ul>	<p><b>General Features</b></p> <p><math>V_{DS} = -60V</math> <math>I_D = -100A</math></p> <p><math>R_{DS(ON)} = 8.5m\Omega</math> (typ.) @ <math>V_{GS} = -10V</math></p> <p>100% UIS Tested 100% <math>R_g</math> Tested</p> 
<p><b>D:TO-252-3L</b></p>    <p>Marking: 100P06</p>	

**Absolute Maximum Ratings (TC=25°C unless otherwise noted)**

Symbol	Parameter	Rating	Unit
<b>Common Ratings</b>			
$V_{DSS}$	Drain-Source Voltage	-60	V
$V_{GSS}$	Gate-Source Voltage	$\pm 20$	
$T_J$	Maximum Junction Temperature	150	°C
$T_{STG}$	Storage Temperature Range	-55 to 150	
$I_S$	Diode Continuous Forward Current	$T_c = 25^\circ C$	A
$I_D$	Continuous Drain Current	$T_c = 25^\circ C$	A
		$T_c = 100^\circ C$	
$I_{DM}$	Pulsed Drain Current	$T_c = 25^\circ C$	$-420^a$
$P_D$	Maximum Power Dissipation	$T_c = 25^\circ C$	W
		$T_c = 100^\circ C$	
$R_{0JC}$	Thermal Resistance-Junction to Case	Steady state	$1.4^\circ C/W$
$R_{0JA}$	Thermal Resistance-Junction to Ambient	Steady state	$50^\circ C/W$
$I_{AS}^b$	Avalanche Current, Single pulse	$L = 0.5mH$	-28 A
$E_{AS}^b$	Avalanche Energy, Single pulse	$L = 0.5mH$	196 mJ

Note a : Pulse width limited by maximum junction temperature.

Note b : UIS tested and pulse width limited by maximum junction temperature (initial temperature  $T_i = 25^\circ C$ ).

**Electrical Characteristics** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

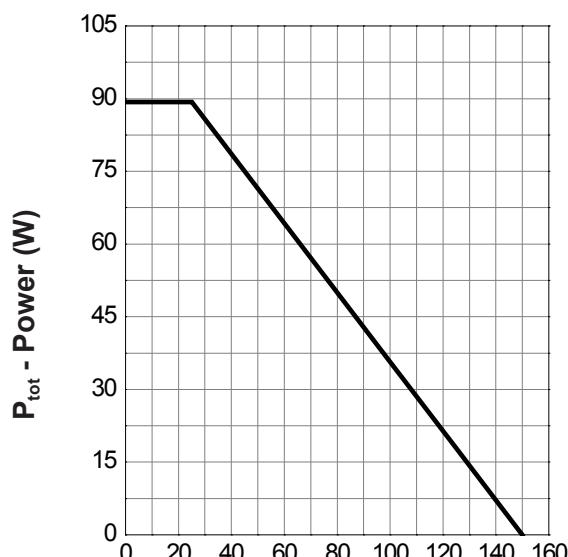
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
<b>Static Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}, I_{DS}=-250\mu\text{A}$	-60	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-48\text{V}, V_{GS}=0\text{V}$ $T_J=85^\circ\text{C}$	-	-	-1	$\mu\text{A}$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=-250\mu\text{A}$	-1	-1.5	-2	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 25\text{V}, V_{DS}=0\text{V}$	-	-	$\pm 100$	nA
$R_{DS(ON)}^{\text{c}}$	Drain-Source On-state Resistance	$V_{GS}=-10\text{V}, I_{DS}=-30\text{A}$	-	8.5	10	$\text{m}\Omega$
		$V_{GS}=-4.5\text{V}, I_{DS}=-30\text{A}$	-	11	14	$\text{m}\Omega$
<b>Diode Characteristics</b>						
$V_{SD}^{\text{c}}$	Diode Forward Voltage	$I_{SD}=-15\text{A}, V_{GS}=0\text{V}$	-	-0.8	-1.1	V
$t_{rr}$	Reverse Recovery Time	$I_{SD}=-30\text{A}, dI_{SD}/dt=100\text{A}/\mu\text{s}$	-	47	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	72	-	nC
<b>Dynamic Characteristics</b> <sup>d</sup>						
$R_G$	Gate Resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, F=1\text{MHz}$	-	2	-	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=-30\text{V},$ Frequency=1.0MHz	-	5800	-	pF
$C_{oss}$	Output Capacitance		-	350	-	
$C_{rss}$	Reverse Transfer Capacitance		-	185	-	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=-30\text{V}, R_L=30\Omega,$ $I_{DS}=-1\text{A}, V_{GEN}=-10\text{V},$ $R_G=6\Omega$	-	23	41	ns
$t_r$	Turn-on Rise Time		-	15	27	
$t_{d(OFF)}$	Turn-off Delay Time		-	114	205	
$t_f$	Turn-off Fall Time		-	47	85	
<b>Gate Charge Characteristics</b> <sup>d</sup>						
$Q_g$	Total Gate Charge	$V_{DS}=-30\text{V}, V_{GS}=-10\text{V},$ $I_{DS}=-30\text{A}$	-	89	125	nC
$Q_{gs}$	Gate-Source Charge		-	21	-	
$Q_{gd}$	Gate-Drain Charge		-	24	-	

Note c : Pulse test ; pulse width $\leq 300\mu\text{s}$ , duty cycle $\leq 2\%$ .

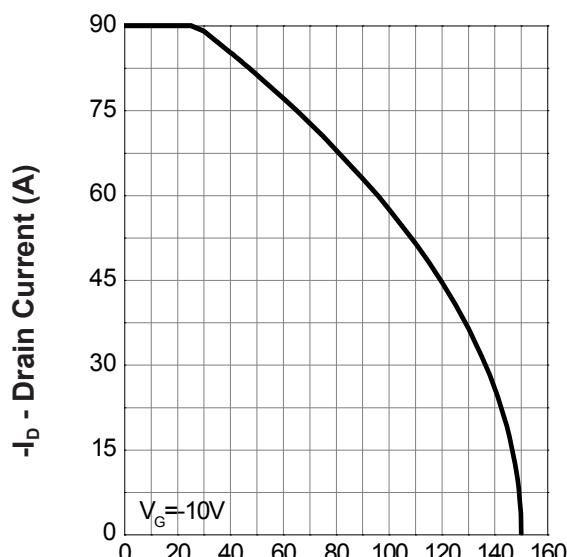
Note d : Guaranteed by design, not subject to production testing.

## Typical Operating Characteristics

**Power Dissipation**

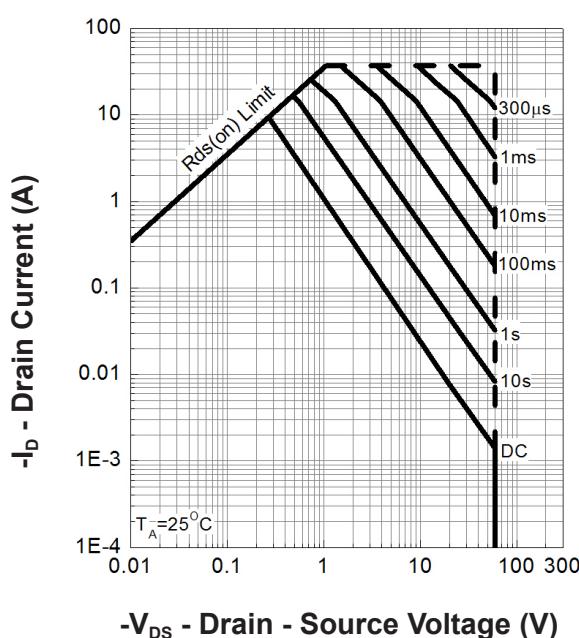


**Drain Current**

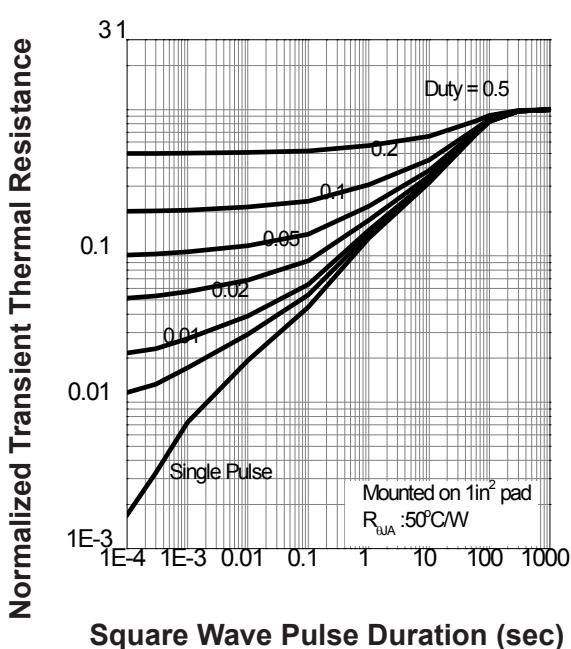


$T_c$  - Case Temperature (°C)

**Safe Operation Area**

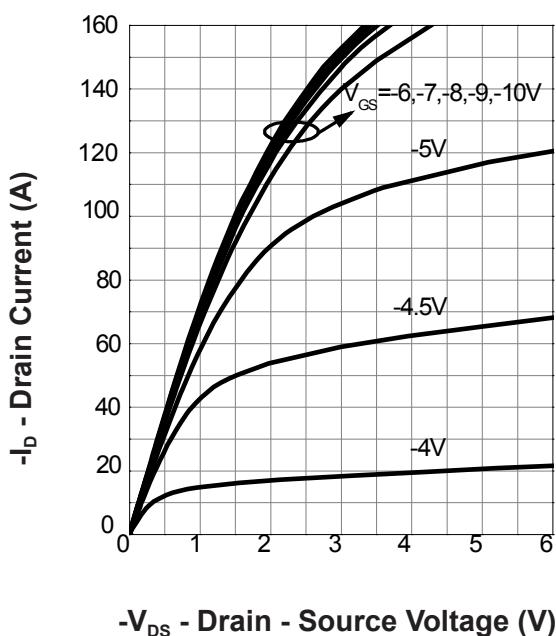


**Thermal Transient Impedance**

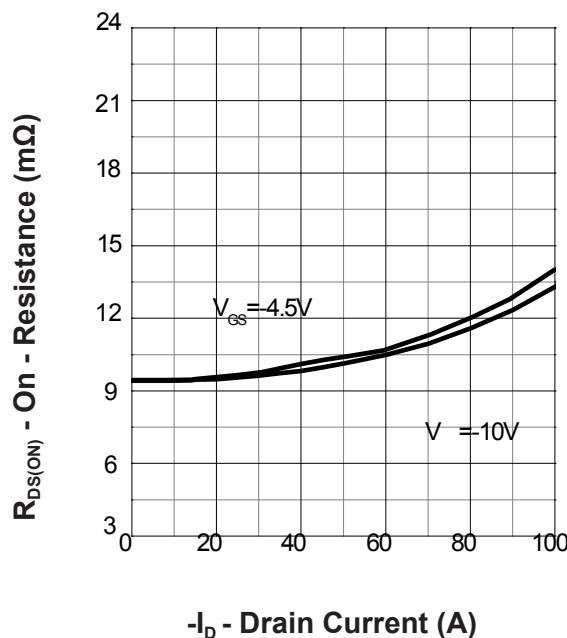


**Square Wave Pulse Duration (sec)**

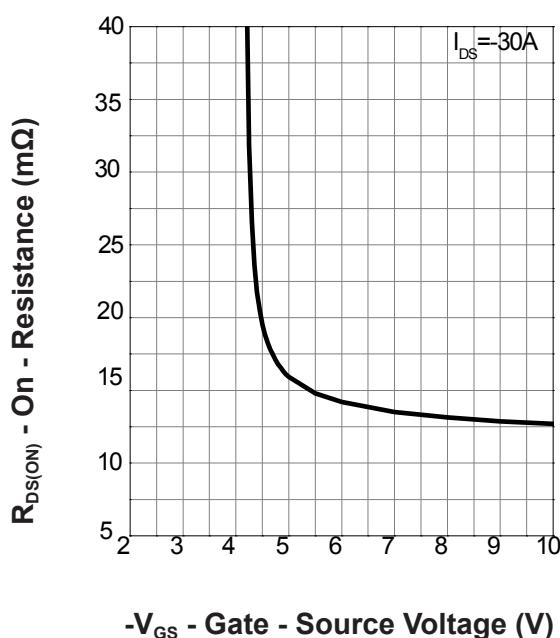
**Output Characteristics**



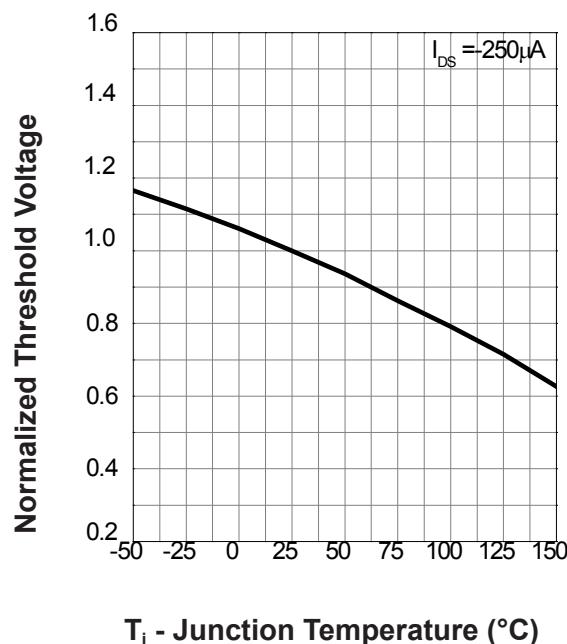
**Drain-Source On Resistance**



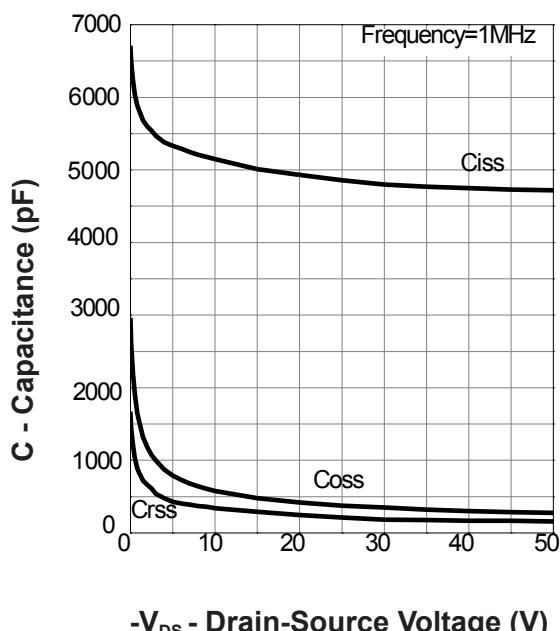
**Gate-Source On Resistance**



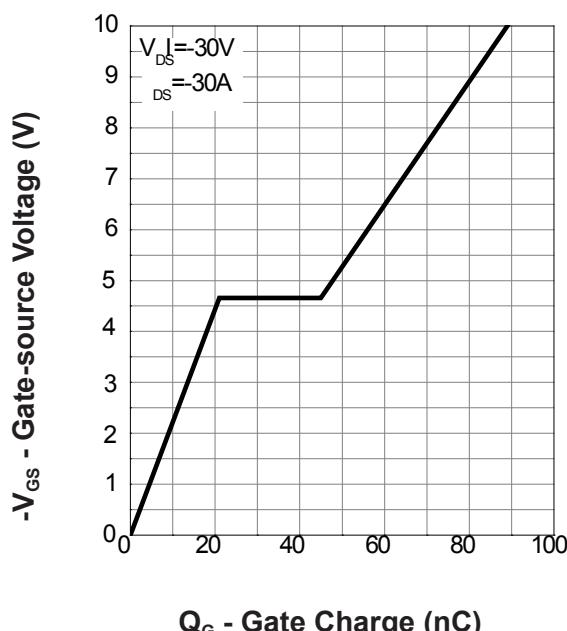
**Gate Threshold Voltage**



**Capacitance**



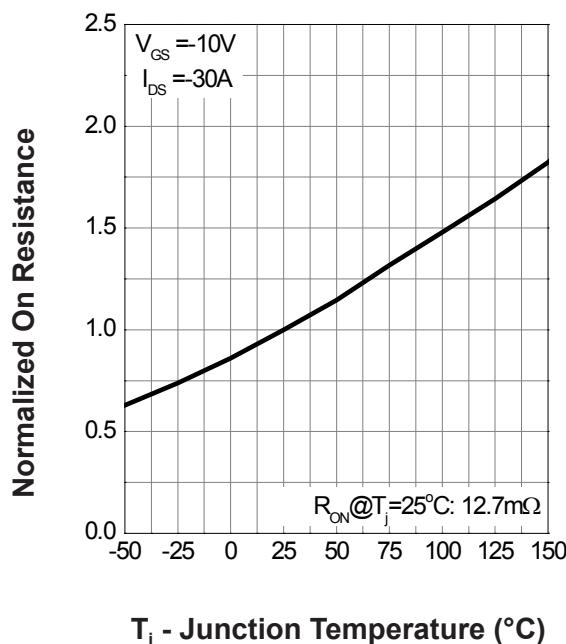
**Gate Charge**



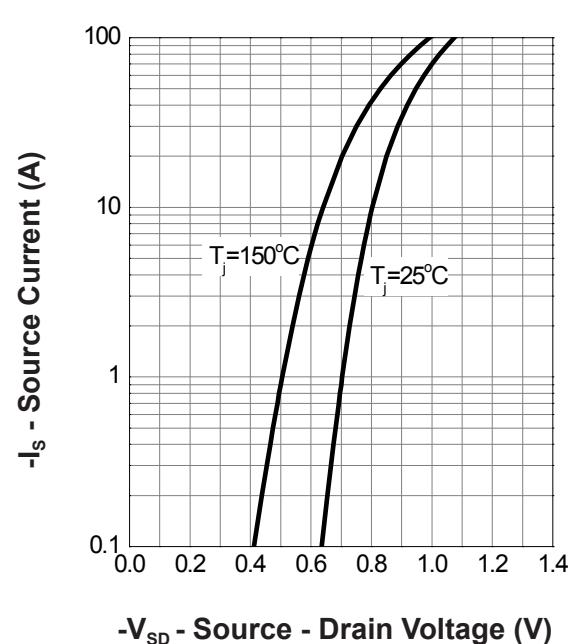
$-V_{DS}$  - Drain-Source Voltage (V)

$Q_G$  - Gate Charge (nC)

**Drain-Source On Resistance**



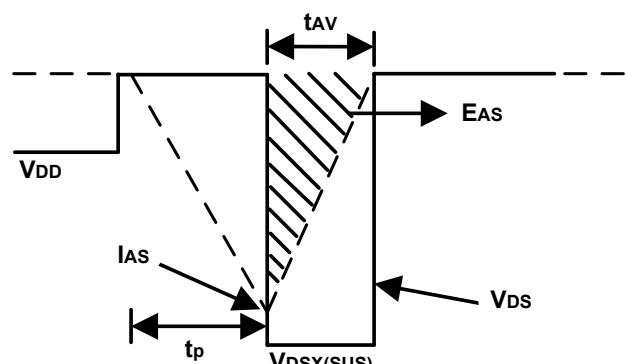
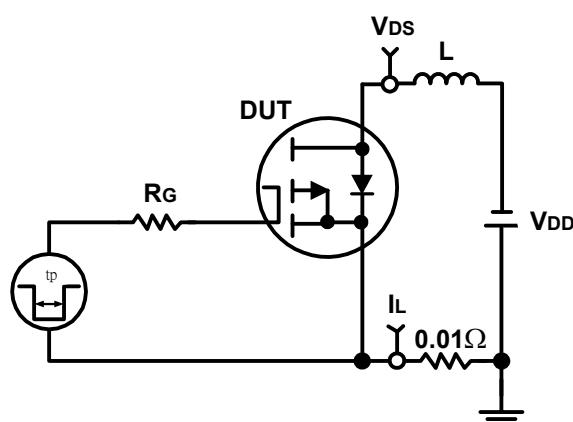
**Source-Drain Diode Forward**



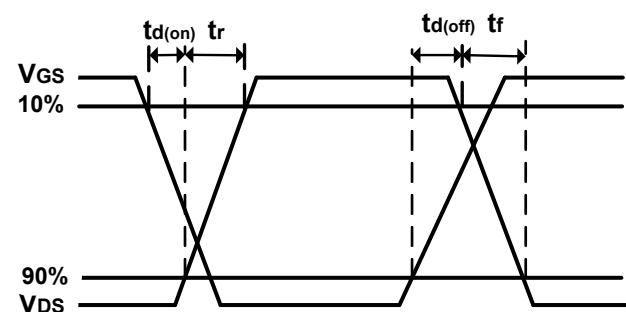
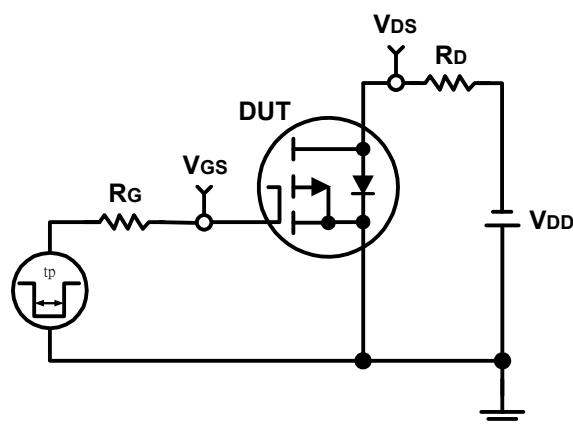
$T_j$  - Junction Temperature (°C)

$-V_{SD}$  - Source - Drain Voltage (V)

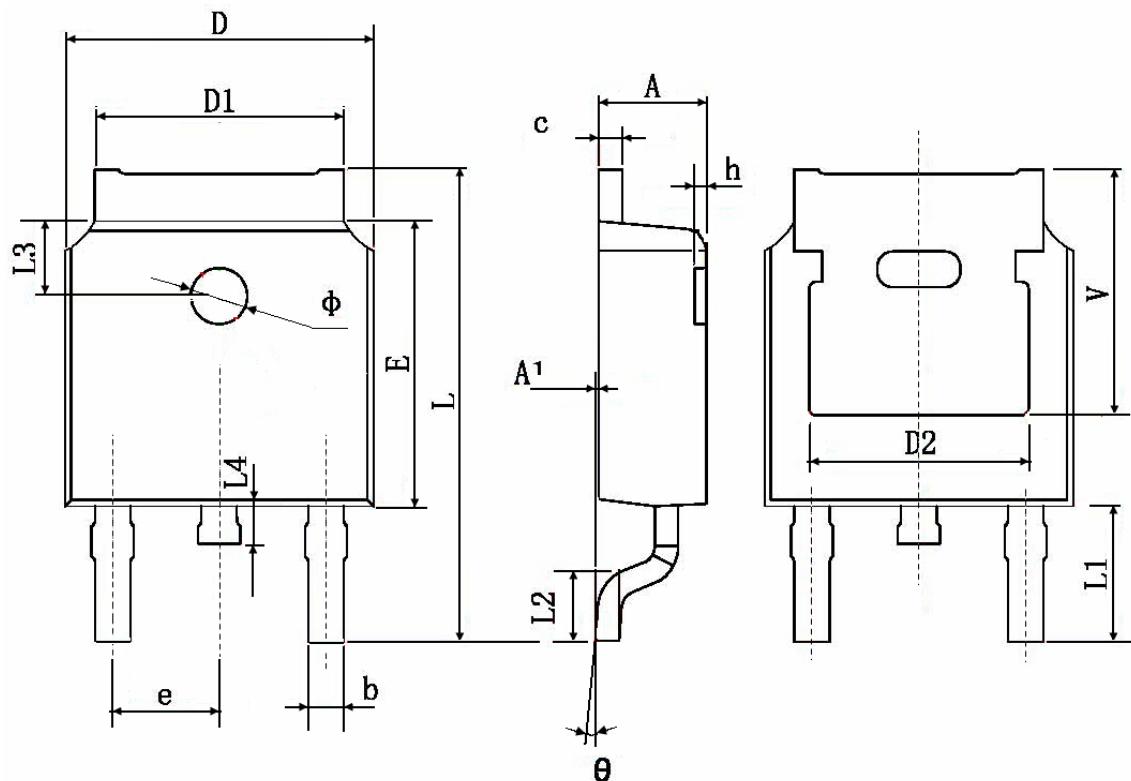
### Avalanche Test Circuit and Waveforms



### Switching Time Test Circuit and Waveforms



## Package Information: TO-252-3L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.660	0.860	0.026	0.034
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 TYP.		0.190 TYP.	
E	6.000	6.200	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.800	10.400	0.386	0.409
L1	2.900 TYP.		0.114 TYP.	
L2	1.400	1.700	0.055	0.067
L3	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.350 TYP.		0.211 TYP.	